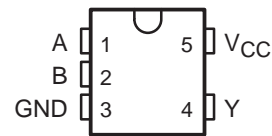


# SN74LVC1G08 SINGLE 2-INPUT POSITIVE-AND GATE

SCES217B – APRIL 1999 – REVISED FEBRUARY 2000

- **EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- **I<sub>off</sub> Feature Supports Partial-Power-Down Mode Operation**
- **Supports 5-V V<sub>CC</sub> Operation**
- **Package Options Include Plastic Small-Outline Transistor (DBV, DCK) Packages**

DBV OR DCK PACKAGE  
(TOP VIEW)



## description

This single 2-input positive-AND gate is designed for 1.65-V to 5.5-V V<sub>CC</sub> operation.

The SN74LVC1G08 performs the Boolean function  $Y = A \cdot B$  or  $Y = \overline{\overline{A} + \overline{B}}$  in positive logic.

This device is fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

The SN74LVC1G08 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

INPUTS		OUTPUT
A	B	Y
H	H	H
L	X	L
X	L	L

## logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



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PRODUCT PREVIEW

# SN74LVC1G08

## SINGLE 2-INPUT POSITIVE-AND GATE

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, $V_{CC}$	–0.5 V to 6.5 V
Input voltage range, $V_I$ (see Note 1)	–0.5 V to 6.5 V
Output voltage range, $V_O$ (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, $I_{IK}$ ( $V_I < 0$ )	–50 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ )	–50 mA
Continuous output current, $I_O$	±50 mA
Continuous current through $V_{CC}$ or GND	±100 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): DBV package	347°C/W
DCK package	389°C/W
Storage temperature range, $T_{stg}$	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.  
 2. The value of  $V_{CC}$  is provided in the recommended operating conditions table.  
 3. The package thermal impedance is calculated in accordance with JESD 51.

### recommended operating conditions (see Note 4)

		MIN	MAX	UNIT	
$V_{CC}$	Supply voltage	Operating	1.65	5.5	V
		Data retention only	1.5		
$V_{IH}$	High-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$		V
		$V_{CC} = 2.3$ V to 2.7 V	1.7		
		$V_{CC} = 3$ V to 3.6 V	2		
		$V_{CC} = 4.5$ V to 5.5 V	$0.7 \times V_{CC}$		
$V_{IL}$	Low-level input voltage	$V_{CC} = 1.65$ V to 1.95 V		$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V		0.7	
		$V_{CC} = 3$ V to 3.6 V		0.8	
		$V_{CC} = 4.5$ V to 5.5 V		$0.3 \times V_{CC}$	
$V_I$	Input voltage	0	5.5	V	
$V_O$	Output voltage	0	$V_{CC}$	V	
$I_{OH}$	High-level output current	$V_{CC} = 1.65$ V		–4	mA
		$V_{CC} = 2.3$ V		–8	
		$V_{CC} = 3$ V		–16	
		$V_{CC} = 4.5$ V		–24	
$I_{OL}$	Low-level output current	$V_{CC} = 1.65$ V		4	mA
		$V_{CC} = 2.3$ V		8	
		$V_{CC} = 3$ V		16	
		$V_{CC} = 4.5$ V		24	
$\Delta t/\Delta v$	Input transition rise or fall rate	$V_{CC} = 1.8$ V ± 0.15 V, 2.5 V ± 0.2 V		20	ns/V
		$V_{CC} = 3.3$ V ± 0.3 V		10	
		$V_{CC} = 5$ V ± 0.5 V		5	
$T_A$	Operating free-air temperature	–40	85	°C	

NOTE 4: All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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# SN74LVC1G08 SINGLE 2-INPUT POSITIVE-AND GATE

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**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER		TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP†	MAX	UNIT
V <sub>OH</sub>		I <sub>OH</sub> = -100 μA	1.65 V to 5.5 V	V <sub>CC</sub> -0.1			V
		I <sub>OH</sub> = -4 mA	1.65 V	1.2			
		I <sub>OH</sub> = -8 mA	2.3 V	1.9			
		I <sub>OH</sub> = -16 mA	3 V	2.4			
		I <sub>OH</sub> = -24 mA		2.3			
		I <sub>OH</sub> = -32 mA	4.5 V	3.8			
V <sub>OL</sub>		I <sub>OL</sub> = 100 μA	1.65 V to 5.5 V			0.1	V
		I <sub>OL</sub> = 4 mA	1.65 V			0.45	
		I <sub>OL</sub> = 8 mA	2.3 V			0.3	
		I <sub>OL</sub> = 16 mA	3 V			0.4	
		I <sub>OL</sub> = 24 mA				0.55	
		I <sub>OL</sub> = 32 mA	4.5 V			0.55	
I <sub>I</sub>	A or B inputs	V <sub>I</sub> = 5.5 V or GND	0 to 5.5 V			±5	μA
I <sub>off</sub>		V <sub>I</sub> or V <sub>O</sub> = 5.5 V	0			±10	μA
I <sub>CC</sub>		V <sub>I</sub> = 5.5 V or GND, I <sub>O</sub> = 0	1.65 V to 5.5 V			10	μA
ΔI <sub>CC</sub>		One input at V <sub>CC</sub> - 0.6 V, Other inputs at V <sub>CC</sub> or GND	3 V to 5.5 V			500	μA
C <sub>i</sub>		V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V				pF

† All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

**switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 4)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 5 V ± 0.5 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>pd</sub>	A or B	Y									ns

**operating characteristics, T<sub>A</sub> = 25°C**

PARAMETER		TEST CONDITIONS	V <sub>CC</sub> = 1.8 V	V <sub>CC</sub> = 2.5 V	V <sub>CC</sub> = 3.3 V	V <sub>CC</sub> = 5 V	UNIT
			TYP	TYP	TYP	TYP	
C <sub>pd</sub>	Power dissipation capacitance	f = 10 MHz					pF

PRODUCT PREVIEW

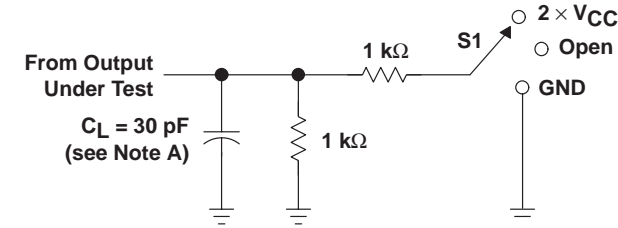


# SN74LVC1G08 SINGLE 2-INPUT POSITIVE-AND GATE

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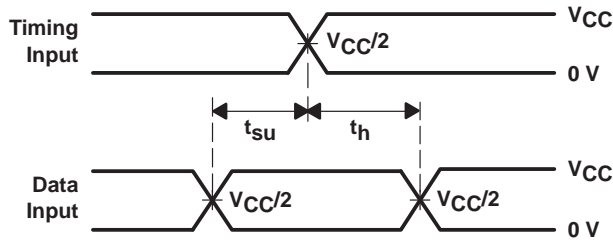
## PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 1.8\text{ V} \pm 0.15\text{ V}$$

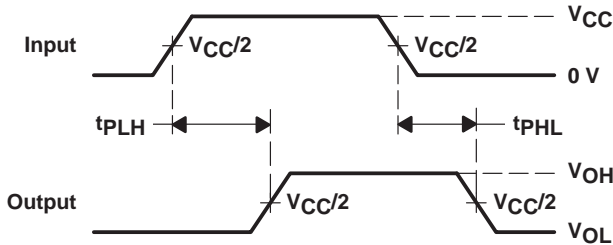


LOAD CIRCUIT

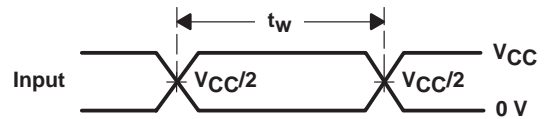
TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	$2 \times V_{CC}$
$t_{PHZ}/t_{PZH}$	GND



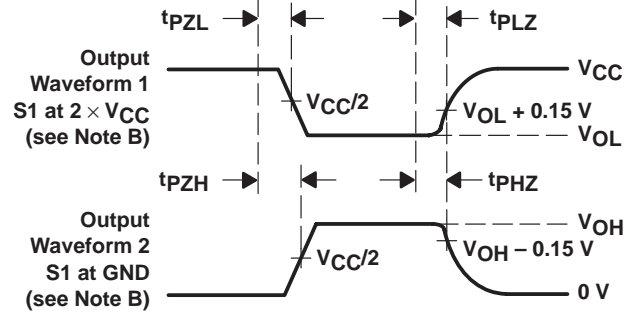
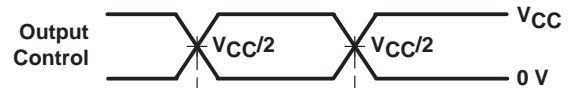
VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES

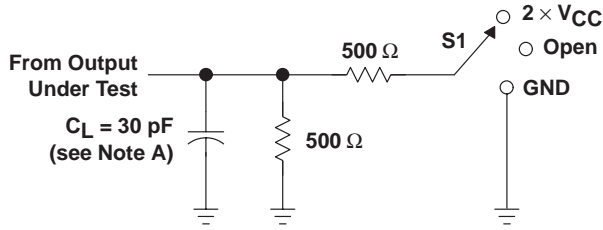
- NOTES:
- $C_L$  includes probe and jig capacitance.
  - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10\text{ MHz}$ ,  $Z_O = 50\ \Omega$ ,  $t_r \leq 2\text{ ns}$ ,  $t_f \leq 2\text{ ns}$ .
  - The outputs are measured one at a time with one transition per measurement.
  - $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
  - $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
  - $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 1. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

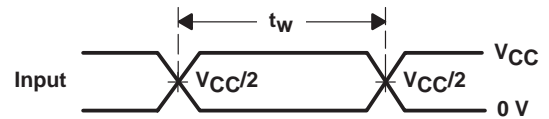
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$

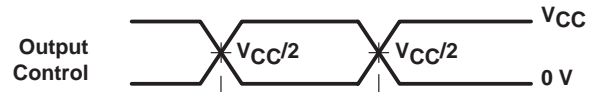
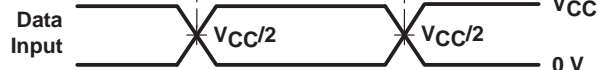


LOAD CIRCUIT

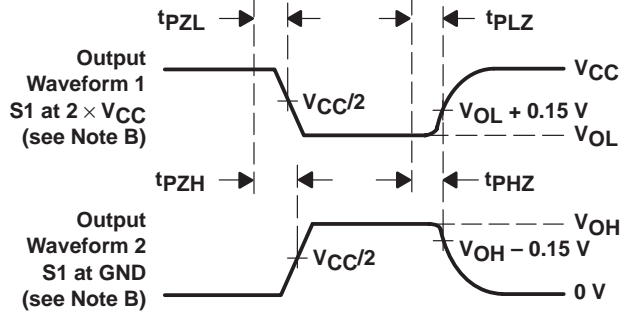
TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	2 $\times$ $V_{CC}$
$t_{PHZ}/t_{PZH}$	GND



VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES

VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES

- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50\ \Omega$ ,  $t_r \leq 2\text{ ns}$ ,  $t_f \leq 2\text{ ns}$ .  
 D. The outputs are measured one at a time with one transition per measurement.  
 E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .  
 F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .  
 G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 2. Load Circuit and Voltage Waveforms

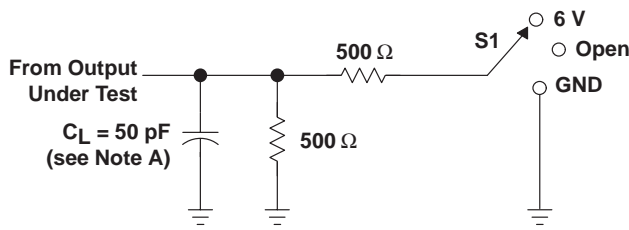
PRODUCT PREVIEW

# SN74LVC1G08 SINGLE 2-INPUT POSITIVE-AND GATE

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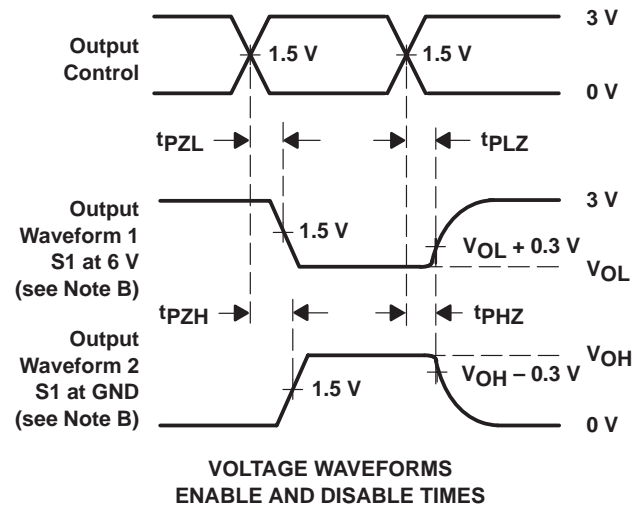
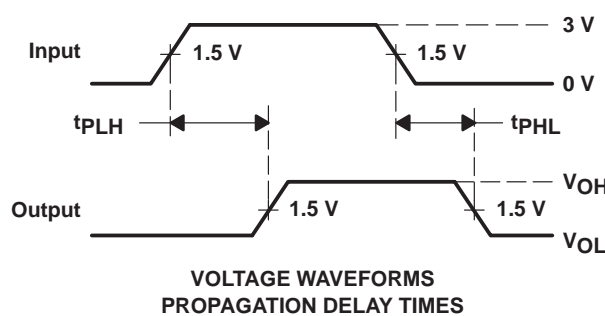
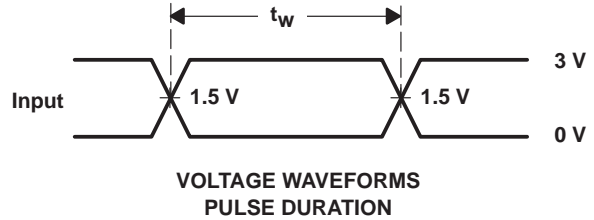
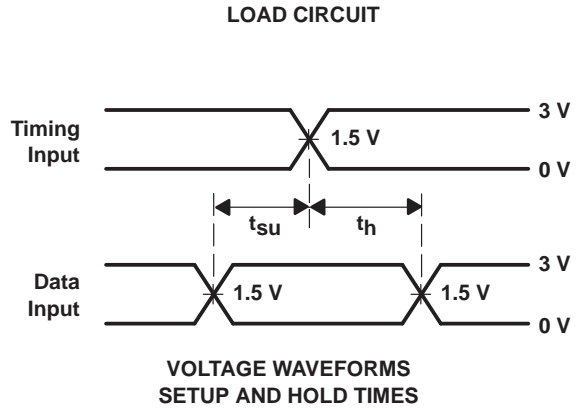
## PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$$



LOAD CIRCUIT

TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	6 V
$t_{PHZ}/t_{PZH}$	GND



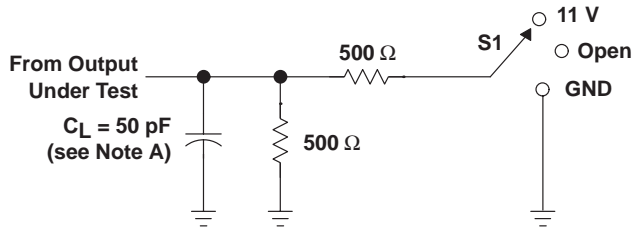
- NOTES:
- $C_L$  includes probe and jig capacitance.
  - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r \leq 2.5 \text{ ns}$ ,  $t_f \leq 2.5 \text{ ns}$ .
  - The outputs are measured one at a time with one transition per measurement.
  - $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
  - $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
  - $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 3. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

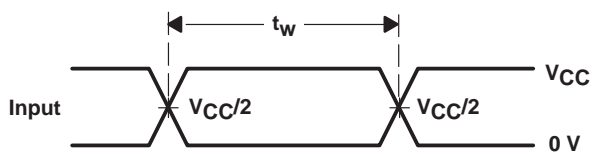
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 5\text{ V} \pm 0.5\text{ V}$

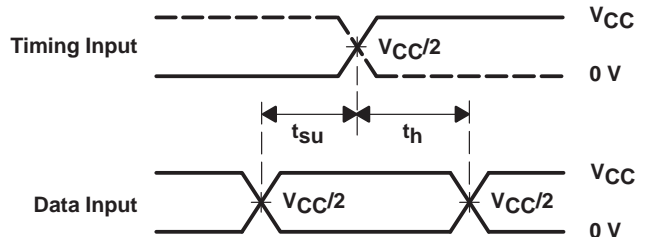


LOAD CIRCUIT

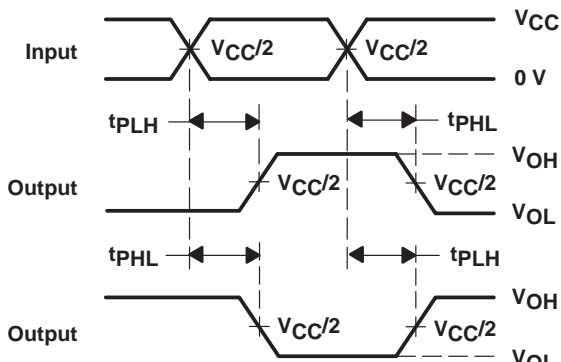
TEST	S1
$t_{PLH}/t_{PHL}$	Open
$t_{PLZ}/t_{PZL}$	11 V
$t_{PHZ}/t_{PZH}$	GND



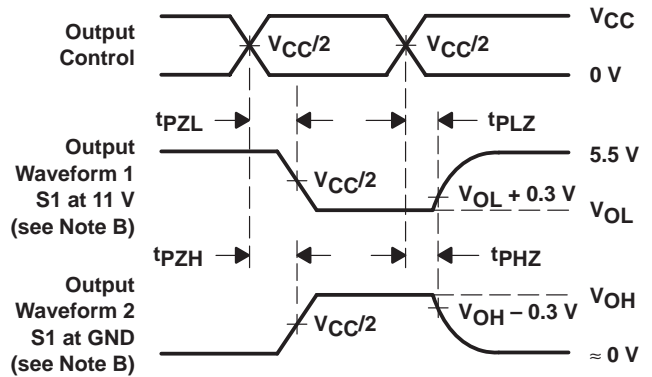
VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES  
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES  
LOW- AND HIGH-LEVEL ENABLING

- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 C. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10\text{ MHz}$ ,  $Z_O = 50\ \Omega$ ,  $t_r \leq 2.5\text{ ns}$ ,  $t_f \leq 2.5\text{ ns}$ .  
 D. The outputs are measured one at a time with one transition per measurement.  
 E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .  
 F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .  
 G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 4. Load Circuit and Voltage Waveforms

PRODUCT PREVIEW

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